

Source of uncertainty	uncorrelated	correlated
<b>Yields</b> $N_i^{\text{obs}}$		
– Data statistics	5 – 25 %	
– Signal extraction	1 – 5 %	
– Beam-gas subtraction		< 1 %
<b>Efficiency correction</b> $(\epsilon_i^{\text{trig/sel}} \epsilon_i^{\text{sel}})^{-1}$		
– MC statistics	1 – 5 %	
– Track finding		6 – 17 %
– Selection		4 %
– Trigger		2 %
– $p_T$ and $y$ shape within bin	0 – 20 %	
– Diffraction modelling		0 – 1 %
– Non-prompt contamination		< 1 %
– Material interactions		< 1 %
<b>Normalization</b> $(L_{\text{int}})^{-1}$		
– Bunch currents		12 %
– Beam widths		5 %
– Beam positions		3 %
– Beam angles		1 %
Sum in quadrature	6 – 28 %	16 – 23 %